

Ion Beam Analysis Techniques for non-Destructive Profiling Studies (Part I)

Thursday, 11 November 2010 09:00 (1:30)

Content

Summary

Primary author(s) : MICHAEL KOKKORIS (National Technical University of Athens, Greece)

Presenter(s) : MICHAEL KOKKORIS (National Technical University of Athens, Greece)

Session Classification : Ion Beam Analysis Techniques for non-Destructive Profiling Studies (Part I)